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Naor WAINER et al.

FILING
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To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	1	4,210,805	1 Jul '80	KOBAYASHI, T. et al.			
	2	4,755,676	5 Jul '88	GAALEMA, S. et al.			
	3	5,677,539	14 Oct '97	APOTOVSKY, B. et al.			
	4	5,777,338	7 Jul '98	HE, Z.			
	5	5,821,539	13 Oct '98	MATZ, R. et al.			
	6	6,034,373	7 Mar '00	SHAHAR, A. et al.			
	7	6,169,287	2 Jan '01	WARBURTON, W. K.			
	8	6,583,420	June 2003	NELSON, et al.			
	9	6,333,504	Dece 2001	LINGREN, et al.			
	10	2002/0079456	June 2002	LINGREN, et al.			
	11	5,500,534	March 1996	ROBINSON, et al.			

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	12	CH 471 392	15 Apr '69	SWITZERLAND				
	13	DE 196 16 545	30 Oct '97	GERMANY				
	14	EP 0 291 351	17 Nov '88	EUROPE				
	15	EP 0 527 373	17 Feb '93	EUROPE				
	16	FR 2 705 791	2 Dec '94	FRANCE				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	17	HE, Z. et al.; "Coplanar Grid Patterns and Their Effect on Energy Resolution of CdZnTe Detectors;" IEEE Nuclear Science Symposium and Medical Imaging Conference; Albuquerque, Mexico; 9-15 November 1997
	18	NAOAKI, I.; JP 02-163691 A; 22 June 1990 & Patent Abstracts of Japan; Vol. 014; No. 422 (P-1104); 12 September 1990

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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